

Notice of References Cited	Application/Control No. 09/877,317	Applicant(s)/Patent Under Reexamination SIE ET AL.	
	Examiner Alina N Boutah	Art Unit 2143	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,771,009 A	06-1998	Nakaya, Yuichiro	709/231
	B.	US-6,418,557 B1	07-2002	Otani, Koji	709/231
	C	US-5,532,735 A	07-1996	Blahut et al.	725/8
	D	US-5,850,218 A	12-1998	LaJoie et al.	725/8
	E	US-5,940,738 A	08-1999	Rao, R. Padmanabha	725/103
	F	US-6,487,722 B1	11-2002	Okura et al.	725/40
	G	US-6,510,555 B1	01-2003	Tsurumoto, Takashi	725/92
	H	US-6,594,826 B1	07-2003	Rao et al.	725/95
	I	US-6,701,528 B1	03-2004	Arsenault et al.	725/89
	J	US-5,682,597 A	10-1997	Ganek et al.	455/3.04
	K	US-2004/0148634 A1	07-2004	Arsenault et al.	725/089
	L	US-2002/0059618 A1	05-2002	Venter, Johan I.J.	725/87
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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